

P-Channel Power MOSFET

CDM5203

SOT-23 Surface Mount Plastic Package RoHS compliant



SOT-23

GENERAL DISCRIPTION:

These P-channel MOSFETs utilize advanced processing techniques to achieve the extremely low onresistance per silicon area. This benefit provides the designer with an extremely efficient device for use in battery and load management applications.

A thermally enhanced large pad lead frame has been incorporated into the standard SOT-23 package to produce a HEXFET Power MOSFET with the industry's smallest footprint. This package, dubbed the Micro3TM, is ideal for applications where printed circuit board space is at a premium. The low profile (<1.1mm) of the Micro3 allows it to fit easily into extremely thin application environments such as portable electronics and PCMCIA cards. The thermal resistance and power dissipation are the best available.

FEATURE

- 1. Ultra Low On-Resistance
- 2. P-Channel MOSFET
- 3. Surface Mount
- 4. Available in Tape & Reel
- 5. Low Gate Charge
- 6. Lead-Free
- 7. Halogen-Free

ABSOLUTE MAXIMUM RATINGS (T_a = 25 °C)

Parameter	SYMBOL	VALUE	UNIT
Drain- Source Voltage	V _{DS}	30	V
Continuous Drain Current, V _{GS} @ 10V @ T _A = 25°C	ا _D	3.0	А
Continuous Drain Current, V _{GS} @ 10V T _A = 70°C	ا _D	2.4	А
Pulsed Drain Current ¹	I _{DM}	24	А
Power Dissipation @T _A = 25°C	P _D	1.25	W
Power Dissipation @T _A = 70°C	P _D	0.80	W
Linear Derating Factor		10	mW/°C
Gate-to-Source Voltage	V _{GS}	±20	V
Junction and Storage Temperature Range	T _J , T _{STG}	-55 to +150	°C

THERMAL RESISTANCE

Maximum Junction-to-Ambient ³	$R_{ extsf{ heta}JA}$	100	°C/W



ELECTRICAL CHARACTERISTICS at T_a = 25 °C

Symbol	Test Condition		Value		
		Min	Тур.	Max	Unit
V _{(BR)DSS}	$V_{GS} = 0V, I_{D} = 250\mu A$				V
Breakdown Voltage Temp. $\Delta V(_{BR)DSS}/$ Reference toCoefficient ΔT_{I}			0.019		V/°C
D	V_{GS} = -10V, I_{D} = 3.0A ²	-	-	98	mΩ
R _{DS(on)}	V_{GS} = -4.5V, I _D = 2.6A ²			165	11122
V _{GS(th)}	$V_{DS} = V_{GS}$, $I_D = 250 \mu A$	1.0		2.5	V
gfs	V _{DS} = -10V, I _D = 3.0A	3.1			S
1.000					μA
'D88					μ, (
- I _{GSS}					nA
ů.	-				nC
J					
	E .				ns
	°				
	V _{GS} = 10V		52		
C _{iss}	$V_{GS} = 0V$		510		
C _{oss}	V _{DS} = 25V		71		pF
C _{rss}	<i>f</i> = 1.0MHz		43		
eristics					
ا _s	MOSFET symbol showing the			1.3	А
I _{SM}	integral reverse p-n junction diode			24	A
V _{SD}	$T_{J} = 25^{\circ}C$, $I_{S} = -1.3A$, $V_{GS} = 0V^{2}$			1.2	V
			17	26	ns
Q _{rr}	$di/dt = -100A/\mu s^2$		12	18	nC
	$\begin{array}{c c} \Delta V(_{BR)DSS}/\\ \Delta T_J \\ \hline & R_{DS(on)} \\ \hline & V_{GS(th)} \\ \hline & gfs \\ \hline & I_{DSS} \\ \hline & I_{CSS} \\ \hline & Q_{gd} \\ \hline & Q_{gs} \\ \hline & Q_{gd} \\ \hline & Q_{gs} \\ \hline & Q_{gd} \\ \hline & Q_{gs} \\ \hline \hline &$	$\begin{array}{c c c c c c c c c c c c c c c c c c c $	$\begin{tabular}{ c c c c c c } \hline Symbol & Iest Condition & Min \\ \hline V_{(BR)DSS} & V_{GS} = 0V, I_D = 250\mu A & 30 \\ \hline \Delta V_{(BR)DSS} & Reference to 25°C, I_D = 1mA & \\ \hline \Delta T_J & V_{GS} = -10V, I_D = 3.0A^2 & \\ \hline V_{GS}(m) & V_{DS} = V_{GS}, I_D = 250\mu A & 1.0 \\ \hline gfs & V_{DS} = -4.5V, I_D = 3.0A^2 & \\ \hline V_{GS}(th) & V_{DS} = V_{GS}, I_D = 250\mu A & 1.0 \\ \hline gfs & V_{DS} = -24V, V_{GS} = 0V & \\ \hline I_{DSS} & V_{DS} = -24V, V_{GS} = 0V & \\ \hline V_{DS} = 24V, V_{GS} = 0V, T_J = 70°C & \\ \hline I_{GSS} & V_{DS} = 24V, V_{GS} = 0V & \\ \hline Q_{g} & I_D = 3.0A & \\ \hline Q_{gg} & V_{DS} = 24V & \\ \hline Q_{gg} & V_{DS} = 24V & \\ \hline Q_{gg} & V_{DS} = 10V^2 & \\ \hline t_{d(on)} & V_{DD} = 15V^2 & \\ \hline t_{r} & I_D = 1.0A & \\ \hline t_{d(off)} & R_G = 6.0\Omega & \\ \hline t_{f} & V_{GS} = 10V & \\ \hline C_{iss} & V_{GS} = 0V & \\ \hline C_{iss} & V_{GS} = 0V & \\ \hline C_{rss} & f = 1.0MHz & \\ \hline eristics & \\ \hline I_S & MOSFET symbol \\ showing the \\ integral reverse \\ \hline P_{-n} junction diode & \hline \\ \hline t_{r_{T}} & T_J = 25°C, I_S = -1.3A, V_{GS} = 0V^2 & \\ \hline t_{r_{T}} & T_J = 25°C, I_F = 1.3A & \\ \hline \end{tabular}$	$\begin{tabular}{ c c c c c c } \hline Symbol & Test Condition & Min & Typ. \\ \hline V_{(BR)DSS} & V_{GS} = 0V, I_D = 250\muA & 30 & \\ \hline & \Delta V(_{BR)DSS} & Reference to 25°C, I_D = 1mA & & 0.019 \\ \hline & \Delta T_J & V_{GS} = -10V, I_D = 3.0A^2 & & \\ \hline & V_{GS}(m) & V_{DS} = V_{GS}, I_D = 250\muA & 1.0 & \\ \hline & V_{GS}(m) & V_{DS} = V_{GS}, I_D = 250\muA & 1.0 & \\ \hline & gfs & V_{DS} = -10V, I_D = 3.0A & 3.1 & \\ \hline & V_{DS} = 24V, V_{GS} = 0V & & \\ \hline & V_{DS} = 24V, V_{GS} = 0V & & \\ \hline & V_{DS} = 24V, V_{GS} = 20V & & \\ \hline & V_{DS} = 24V, V_{GS} = 20V & & \\ \hline & V_{DS} = 24V, V_{GS} = 20V & & \\ \hline & V_{DS} = 24V, V_{GS} = 10V^2 & & 1.6 \\ \hline & t_{d(on)} & V_{DD} = 15V^2 & & 12 \\ \hline & t_t & I_D = 1.0A & & 18 \\ \hline & t_{d(off)} & R_G = 6.0\Omega & & 88 \\ \hline & t_t & V_{GS} = 10V & & 52 \\ \hline & C_{iss} & V_{GS} = 0V & & 510 \\ \hline & C_{oss} & V_{GS} = 25V & & 71 \\ \hline & C_{rss} & f = 1.0MHz & & 43 \\ \hline eristics & \\ \hline & I_S & MOSFET symbol \\ showing the \\ integral reverse \\ \hline & I_S & MOSFET symbol \\ showing the \\ integral reverse \\ \hline & P-n junction diode & \hline & & \\ \hline & V_{SD} & T_J = 25°C, I_S = -1.3A, V_{GS} = 0V^2 & & \\ \hline & t_{rr} & T_J = 25°C, I_F = 1.3A & & 17 \\ \hline \end{array}$	$\begin{tabular}{ c c c c c c c c c c c c c c c c c c c$

Note:

1. Repetitive rating; pulse width limited by max. junction temperature

2. Pulse width $\leq 400 \mu s$; duty cycle $\leq 2\%$

3. Surface mounted on FR-4 board, t \leq 5sec

4. For PNP device voltage and current values will be negative (-).

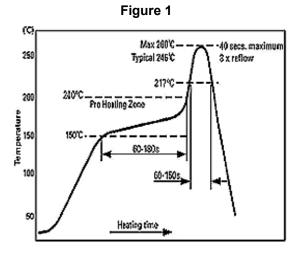


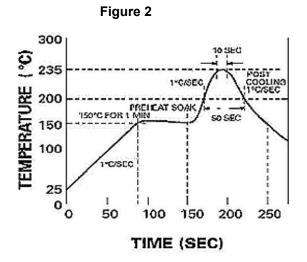
Recommended Reflow Solder Profiles

The recommended reflow solder profiles for Pb and Pb-free devices are shown below.

Figure 1 shows the recommended solder profile for devices that have Pb-free terminal plating, and where a Pb-free solder is used.

Figure 2 shows the recommended solder profile for devices with Pb-free terminal plating used with leaded solder, or for devices with leaded terminal plating used with a leaded solder.





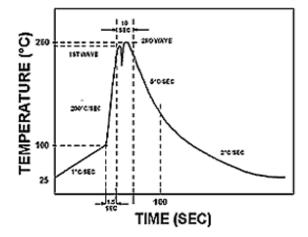
Reflow profiles in tabular form

Profile Feature	Sn-Pb System	Pb-Free System
Average Ramp-Up Rate	~3°C/second	~3°C/second
Preheat – Temperature Range – Time	150-170°C 60-180 seconds	150-200°C 60-180 seconds
Time maintained above: – Temperature – Time	200°C 30-50 seconds	217°C 60-150 seconds
Peak Temperature	235°C	260°C max.
Time within +0 -5°C of actual Peak	10 seconds	40 seconds
Ramp-Down Rate	3°C/second max.	6°C/second max.

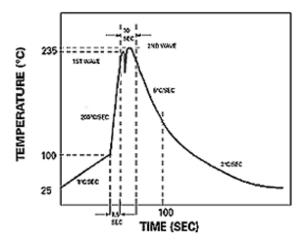


Recommended Wave Solder Profiles

The Recommended solder Profile For Devices with Pb-free terminal plating where a Pb-free solder is used



The Recommended solder Profile For Devices with Pb-free terminal plating used with leaded solder, or for devices with leaded terminal plating used with leaded solder

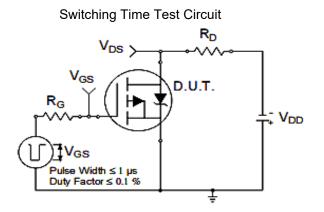


Wave Profiles in Tabular Form

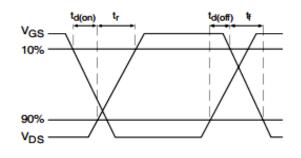
Profile Feature	Sn-Pb System	Pb-Free System
Average Ramp-Up Rate	~200°C/second	~200°C/second
Heating rate during preheat	Typical 1-2, Max 4°C/sec	Typical 1-2, Max 4°C/Sec
Final preheat Temperature	Within 125°C of Solder Temp	Within 125°C of Solder Temp
Peak Temperature	235°C	260°C max.
Time within +0 -5°C of actual Peak	10 seconds	10 seconds
Ramp-Down Rate	5°C/second max.	5°C/second max



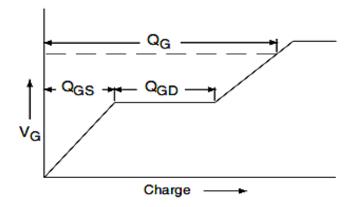
TEST CIRCUIT AND DIAGRAMS



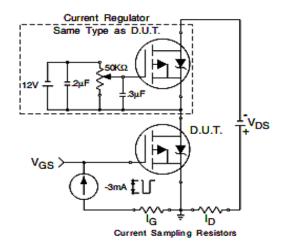
Switching Time Waveforms



Basic Gate Charge Waveform

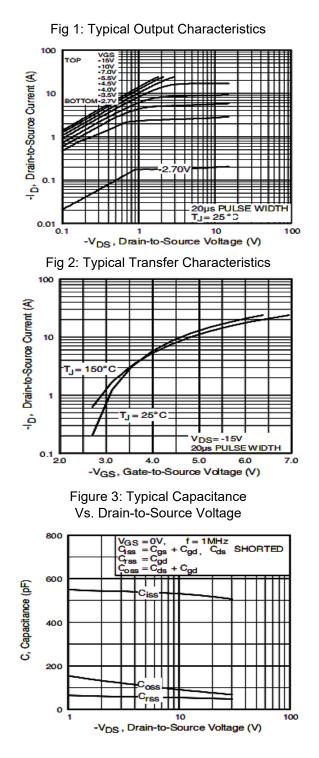


Gate Charge Test Circuit





Typical Characteristic Curves





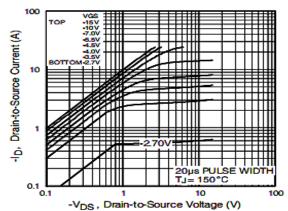


Fig 5: Normalized On-Resistance Vs. Temperature

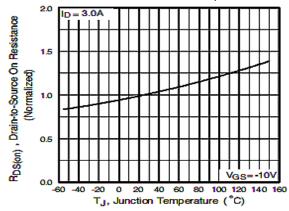
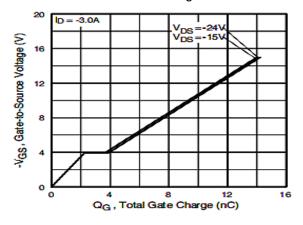


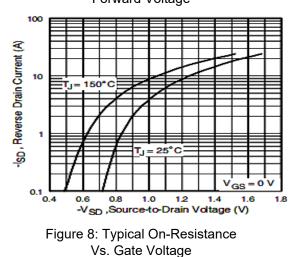
Figure 6: Typical Gate Charge Vs. Gate-to-Source Voltage





Typical Characteristic Curves

Figure 7. Typical Source-Drain Diode Forward Voltage



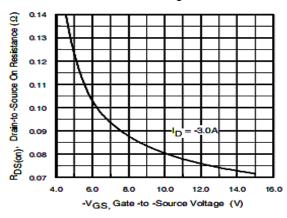
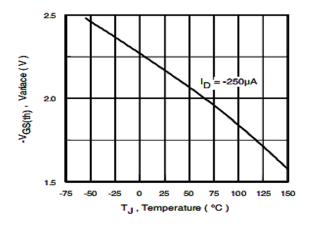


Fig 9: Threshold Voltage Vs. Temperature





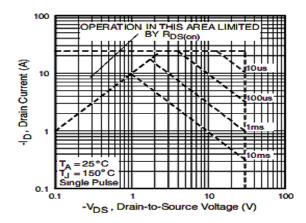


Fig 11: Typical On-Resistance Vs. Drain Current

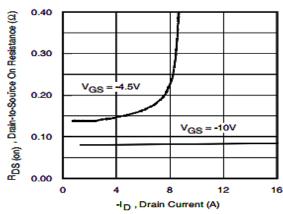
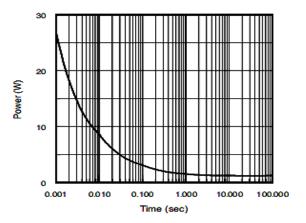


Fig 12: Typical Power Vs. Time





Typical Characteristic Curves

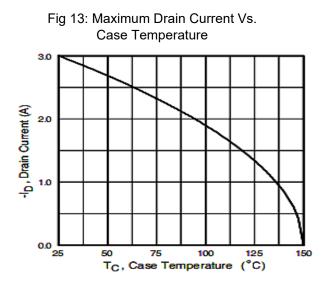
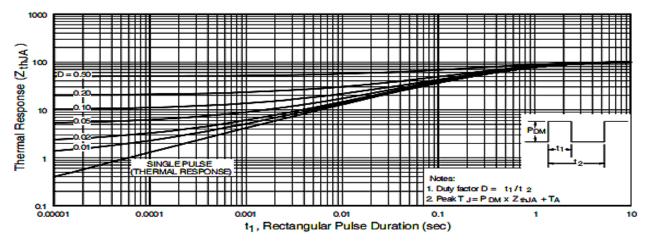
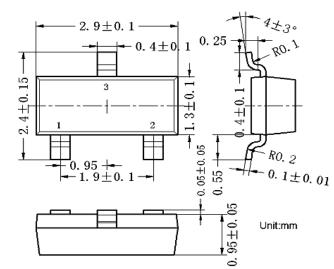


Fig 14: Maximum Effective Transient Thermal Impedance, Junction-to-Ambient





PACKAGE DETAILS



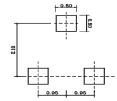
SOT-23 Formed SMD Package

Pin configuration

- 1. Gate
- 2. Source
- 3. Drain

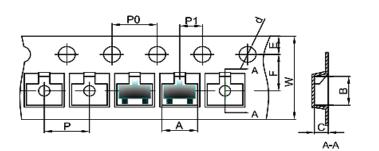


Recommend PCB solder land [Unit: mm]





SOT-23 Embossed Carrier Tape

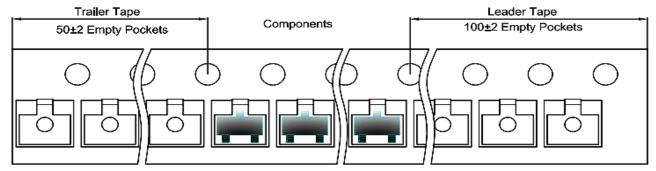


Packaging Description:

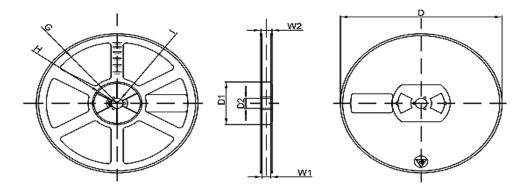
SOT-23 parts are shipped in tape. The carrier tape is made from a dissipative (carbon filled) polycarbonate resin. The cover tape is a multilayer film (Heat Activated Adhesive in nature) primarily composed of polyester film, adhesive layer, sealant, and anti-static sprayed agent. These reeled parts in standard option are shipped with 3,000 units per 7" or 17.8cm diameter reel. The reels are clear in color and is made of polystyrene plastic (anti-static coated).

Dimensions are in millimeter										
Pkg type	А	В	С	d	E	F	P0	Р	P1	w
SOT-23	3.15	2.77	1.22	Ø1.50	1.75	3.50	4.00	4.00	2.00	8.00

SOT-23 TAPE LEADER & TRAILAR



SOT-23 REEL



Dimensions are in millimeter								
Reel Option	D	D1	D2	G	н	I	W1	W2
7"Dia	Ø178.00	54.40	13.00	R78.00	R25.60	R6.50	9.50	12.30

	REEL	Reel Size	Box	Box Size(mm)	Carton	Carton Size(mm)	G.W.(kg)
[3000 pcs	7 Inch	45,000 pcs	203×203×195	180,000 pcs	438×438×220	



Recommended Product Storage Environment for Discrete Semiconductor Devices

This storage environment assumes that the Diodes and transistors are packed properly inside the original packing.

- · Temperature 5 °C to 30 °C
- · Humidity between 40 to 70 %RH
- · Air should be clean.
- · Avoid harmful gas or dust.
- · Avoid outdoor exposure or storage in areas subject to rain or water spraying .
- · Avoid storage in areas subject to corrosive gas or dust. Product shall not be stored in areas exposed to direct sunlight.
- · Avoid rapid change of temperature.
- · Avoid condensation.
- · Mechanical stress such as vibration and impact shall be avoided.
- $\cdot\,$ The product shall not be placed directly on the floor.
- The product shall be stored on a plane area. They should not be turned upside down. They should not be placed against the wall.

Shelf Life

The shelf life of products is the period from product manufacture to shipment to customers. The product can be unconditionally shipped within this period. The period is defined as 2 years.

Floor Life

When the products are opened from the original packing, the floor life will start. For this, the following JEDEC table may be referred:

	JEDEC MSL Level						
Level	Time	Condition					
1	Unlimited	≤30 °C / 85% RH					
2	1 Year	≤30 °C / 60% RH					
2a	4 Weeks	≤30 °C / 60% RH					
3	168 Hours	≤30 °C / 60% RH					
4	72 Hours	≤30 °C / 60% RH					
5	48 Hours	≤30 °C / 60% RH					
5a	24 Hours	≤30 °C / 60% RH					
6	Time on Label(TOL)	≤30 °C / 60% RH					